# **HCPL-261A, HCPL-061A, HCPL-263A, HCPL-063A HCPL-261N, HCPL-061N, HCPL-263N, HCPL-063N** HCMOS Compatible, High CMR, 10 MBd Optocouplers



# **Data Sheet**



## **Description**

The HCPL-261A family of optically coupled gates shown on this data sheet provide all the benefits of the industry standard 6N137 family with the added benefit of HCMOS compatible input current. This allows direct interface to all common circuit topologies without additional LED buffer or drive components. The Al-GaAs LED used allows lower drive currents and reduces degradation by using the latest LED technology. On the single channel parts, an enable output allows the detector to be strobed. The output of the detector IC is an open collector schottky-clamped transistor. The internal shield provides a minimum common mode transient immunity of 1000V/µs for the HCPL-261A family and 15000 V/µs for the HCPL-261N family.

## **Functional Diagram**

**ON OFF** **NC NC**

**L H**



#### The connection of a 0.1 µF bypass capacitor between pins 5 and 8 is required.

## **Features**

- HCMOS/LSTTL/TTL performance compatible
- 1000 V/µs minimum Common Mode Rejection (CMR) at  $V_{CM}$  = 50 V (HCPL-261A family) and 15 kV/ $\mu$ s minimum CMR at  $V_{CM}$  = 1000 V (HCPL-261N family)
- High speed: 10 MBd typical
- AC and DC performance specified over industrial temperature range -40°C to +85°C
- Available in 8 pin DIP, SOIC-8 packages
- Safety approval:
	- UL recognized per UL1577 3750V rms for 1 minute and  $5000V_{rms}$  for 1 minute (Option 020)
	- CSA Approved
	- IEC/EN/DIN EN 60747-5-5 approved

#### **Applications**

- Low input current (3.0 mA) HCMOS compatible version of 6N137 optocoupler
- Isolated line receiver
- Simplex/multiplex data transmission
- Computer-peripheral interface
- Digital isolation for A/D, D/A conversion
- Switching power supplies
- Instrumentation input/output isolation
- Ground loop elimination
- Pulse transformer replacement

*CAUTION: It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.*

#### **Selection Guide**



#### **Notes:**

1. Technical data are on separate Avago publications.

2. 15 kV/ $\mu$ s with V<sub>CM</sub> = 1 kV can be achieved using Avago application circuit.

3. Enable is available for single channel products only, except for HCPL-193x devices.

#### **Schematic**



**USE OF A 0.1 µF BYPASS CAPACITOR CONNECTED BETWEEN PINS 5 AND 8 IS RECOMMENDED (SEE NOTE 16).**



## **Ordering Information**

HCPL-xxxx is UL Recognized with 3750  $V_{rms}$  for 1 minute per UL1577.



To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry. Combination of Option 020 and Option 060 is not available.

Example 1:

HCPL-261A-560E to order product of 300mil DIP Gull Wing Surface Mount package in Tape and Reel packaging with IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Example 2:

HCPL-263N to order product of 300mil DIP package in tube packaging and non RoHS compliant.

Option datasheets are available. Contact your Avago sales representative or authorized distributor for information. Remarks: The notation '#XXX' is used for existing products, while (new) products launched since 15th July 2001 and RoHS compliant option will use '-XXXE'.

### **HCPL-261A/261N/263A/263N Outline Drawing**

#### **Pin Location (for reference only)**





**DIMENSIONS IN MILLIMETERS AND (INCHES).**

**\* MARKING CODE LETTER FOR OPTION NUMBERS. "L" = OPTION 020**

**OPTION NUMBERS 300 AND 500 NOT MARKED.**

**NOTE: FLOATING LEAD PROTRUSION IS 0.25 mm (10 mils) MAX.**

#### **Figure 1. 8-Pin dual in-line package device outline drawing.**



**Figure 2. Gull wing surface mount option #300.**

#### **HCPL-061A/061N/063A/063N Outline Drawing**



**45 X 0.432 (0.017) 0.228 ± 0.025 (0.009 ± 0.001)**  $0.305$  MIN.<br>(0.012) **0.203 ± 0.102 (0.008 ± 0.004) 7.49 (0.295) 1.9 (0.075) 0.64 (0.025)**

**LAND PATTERN RECOMMENDATION**

**Figure 3. 8-Pin Small Outline Package Device Drawing.**

**NOTE: FLOATING LEAD PROTRUSION IS 0.15 mm (6 mils) MAX.**

## **Solder Reflow Profile**

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision). Non-Halide Flux should be used.

## **Regulatory Information**

The HCPL-261A and HCPL-261N families have been approved by the following organizations:

#### **UL**

Recognized under UL 1577, Component Recognition Program, File E55361.

#### **CSA**

Approved under CSA Component Acceptance Notice #5, File CA 88324.

### **IEC/EN/DIN EN 60747-5-5**

## **Insulation and Safety Related Specifications**



Option 300 – surface mount classification is Class A in accordance with CECC 00802.

## **IEC/EN/DIN EN 60747-5-5 Insulation Characteristics\***



\* Refer to the front of the optocoupler section of the current catalog, under Product Safety Regulations section IEC/EN/DIN EN 60747-5-5, for a detailed description.

## **Absolute Maximum Ratings**



## **Recommended Operating Conditions**



## **Electrical Specifications**

Over recommended operating temperature ( $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ ) unless otherwise specified.



\*All typical values at T<sub>A</sub> = 25°C, V<sub>cc</sub> = 5 V

\*\*Single Channel Products only (HCPL-261A/261N/061A/061N)

\*\*\*Dual Channel Products only (HCPL-263A/263N/063A/063N)

## **Switching Specifications**

Over recommended operating temperature ( $T_A = -40^{\circ}C$  to  $+85^{\circ}C$ ) unless otherwise specified.



\*All typical values at  $T_A = 25$ °C, V<sub>cc</sub> = 5 V.

# **Common Mode Transient Immunity Specifications, All values at**  $T_A = 25^{\circ}C$



#### **Package Characteristics**

All Typicals at  $T_a = 25^{\circ}C$ 



\*Ratings apply to all devices except otherwise noted in the Package column.

\*\*The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating. For the continuous voltage rating refer to the IEC/EN/DIN EN 60747-5-5 Insulation Characteristics Table (if applicable), your equipment level safety specification or Avago Application Note 1074 entitled "Optocoupler Input-Output Endurance Voltage." †For 8-pin DIP package devices (HCPL-261A/261N/263A/263N) only.

**Notes:**

- 1. Peaking circuits may be used which produce transient input currents up to 30 mA, 50 ns maximum pulse width, provided the average current does not exceed 10 mA.
- 2. 1 minute maximum.
- 3. Derate linearly above 80 °C free-air temperature at a rate of 2.7 mW/°C for the SOIC-8 package.
- 4. Each channel.
- 5. Device considered a two-terminal device: Pins 1, 2, 3, and 4 shorted together and Pins 5, 6, 7, and 8 shorted together.
- 6. In accordance with UL1577, each optocoupler is proof tested by applying an insulation test voltage ≥4500 V<sub>BMS</sub> for 1 second (leakage detection current limit,  $I_{10} \leq 5 \mu A$ ). This test is performed before the 100% production test for partial discharge (method b) shown in the IEC/EN/ DIN EN 60747-5-5 Insulation Characteristics Table, if applicable.
- 7. In accordance with UL1577, each optocoupler is proof tested by applying an insulation test voltage ≥6000 V<sub>pMS</sub> for 1 second (leakage detection current limit,  $I_{10} \leq 5 \mu A$ ).
- 8. Measured between the LED anode and cathode shorted together and pins 5 through 8 shorted together.
- 9. The t<sub>PLH</sub> propagation delay is measured from the 1.75 mA point on the falling edge of the input pulse to the 1.5 V point on the rising edge of the output pulse.
- 10. The t<sub>PHI</sub> propagation delay is measured from the 1.75 mA point on the rising edge of the input pulse to the 1.5 V point on the falling edge of the output pulse.
- 11. Propagation delay skew (t<sub>psk</sub>) is equal to the worst case difference in t<sub>PLH</sub> and/or t<sub>PHL</sub> that will be seen between any two units under the same test conditions and operating temperature.
- 12. Single channel products only (HCPL-261A/261N/061A/061N).
- 13. Common mode transient immunity in a Logic High level is the maximum tolerable  $|dV_{CM}/dt|$  of the common mode pulse,  $V_{CM}$  to assure that the output will remain in a Logic High state (i.e.,  $\mathsf{V}_{\mathsf{o}} >$  2.0 V).
- 14. Common mode transient immunity in a Logic Low level is the maximum tolerable  $|dV_{CM}/dt|$  of the common mode pulse,  $V_{CM}$  to assure that the output will remain in a Logic Low state (i.e.,  $V_0 < 0.8$  V).
- 15. For sinusoidal voltages

 $(|dV_{\text{CM}}/dt|)$ max =  $\pi f_{\text{CM}}V_{\text{CM}(P\text{-}P)}$ .

- 16. Bypassing of the power supply line is required with a 0.1 µF ceramic disc capacitor adjacent to each optocoupler as shown in Figure 19. Total lead length between both ends of the capacitor and the isolator pins should not exceed 10 mm.
- 17. Pulse Width Distortion (PWD) is defined as the difference between  $t_{PLH}$  and  $t_{PHL}$  for any given device.
- 18. No external pull up is required for a high logic state on the enable input of a single channel product. If the V<sub>E</sub> pin is not used, tying V<sub>E</sub> to V<sub>cc</sub> will result in improved CMR performance.
- 19. Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together. For dual channel parts only.



**Figure 4. Typical high level output current vs. temperature.**



**Figure 5. Low level output current vs. temperature.**



**Figure 6. Typical diode input forward current characteristic.**





**Figure 7. Typical output voltage vs. forward input current.**





**Figure 9. Test circuit for t<sub>PHL</sub> and t<sub>PLH</sub>.** 



**temperature.**



**Figure 11. Typical propagation delay vs. temperature.**



**Figure 12. Typical propagation delay vs. pulse input current.**





**Figure 13. Typical pulse width distortion vs. temperature.**

**Figure 14. Typical rise and fall time vs. temperature.**



Figure 15. Test circuit for t<sub>EHL</sub> and t<sub>ELH</sub>.



**Figure 16. Typical enable propagation delay vs. temperature. HCPL-261A/-261N/-061A/-061N Only.**



**Figure 17. Test circuit for common mode transient immunity and typical waveforms.**



**Figure 18. Thermal derating curve, dependence of safety limiting value with case temperature per IEC/EN/DIN EN 60747-5-5.**

**SINGLE CHANNEL PRODUCTS**



**DUAL CHANNEL PRODUCTS**



**Figure 19. Recommended printed circuit board layout.**



**\* HIGHER CMR MAY BE OBTAINABLE BY CONNECTING PINS 1, 4 TO INPUT GROUND (GND1).**

\*Higher CMR may be obtainable by connecting pins 1, 4 to input ground (Gnd1).

**Figure 20. Recommended drive circuit for HCPL-261A/-261N families for high-CMR (similar for HCPL-263A/-263N).**

## **Application Information**

Common-Mode Rejection for HCPL-261A/HCPL-261N Families:

Figure 20 shows the recommended drive circuit for the HCPL-261N/- 261A for optimal common-mode rejection performance. Two main points to note are:

- 1. The enable pin is tied to  $V_{cc}$  rather than floating (this applies to single-channel parts only).
- 2. Two LED-current setting resistors are used instead of one. This is to balance  $I_{LED}$  variation during common-mode transients.

If the enable pin is left floating, it is possible for common-mode transients to couple to the enable pin, resulting in common-mode failure. This failure mechanism only occurs when the LED is on and the output is in the Low State. It is identified as occurring when the transient output voltage rises above 0.8 V. Therefore, the enable pin should be connected to either  $V_{cc}$  or logic-level high for best common-mode performance with the output low (CMR<sub>L</sub>). This failure mechanism is only present in single-channel parts (HCPL-261N, -261A, -061N, -061A) which have the enable function.

Also, common-mode transients can capacitively couple from the LED anode (or cathode) to the output-side ground causing current to be shunted away from the LED (which can be bad if the LED is on) or conversely cause current to be injected into the LED (bad if the LED is meant to be off). Figure 21 shows the parasitic capacitances which exists between LED anode/cathode and output ground ( $C_{LA}$  and  $C_{LC}$ ). Also shown in Figure 21 on the input side is an ACequivalent circuit.

Table 1 indicates the directions of  $I_{\text{LP}}$  and  $I_{\text{LN}}$  flow depending on the direction of the common-mode transient.

For transients occurring when the LED is on, commonmode rejection (CMR $_{\mathsf{L'}}$  since the output is in the "low" state) depends upon the amount of LED current drive (I<sub>F</sub>). For conditions where  $I_{\epsilon}$  is close to the switching threshold (I<sub>TH</sub>), CMR<sub>L</sub> also depends on the extent which I<sub>LP</sub> and I<sub>LN</sub> balance each other. In other words, any condition where common-mode transients cause a momentary decrease in I<sub>F</sub> (i.e. when dV<sub>cM</sub>/dt>0 and  $\vert I_{\vert_{\text{FP}}}\vert > \vert I_{\vert_{\text{FN}}}\vert$ , referring to Table 1) will cause common-mode failure for transients which are fast enough.

Likewise for common-mode transients which occur when the LED is off (i.e. CMR $_{H}$ , since the output is "high"), if an imbalance between  $I_{\text{LP}}$  and  $I_{\text{IN}}$  results in a transient I<sub>F</sub> equal to or greater than the switching threshold of the optocoupler, the transient "signal" may cause the output to spike below 2 V (which constitutes a CMR<sub>H</sub> failure).

By using the recommended circuit in Figure 20, good CMR can be achieved. (In the case of the -261N families, a minimum CMR of 15 kV/µs is guaranteed using this circuit.) The balanced  $I_{LED}$ -setting resistors help equalize  $I_{LP}$ and  $I_{\text{LN}}$  to reduce the amount by which  $I_{\text{LED}}$  is modulated from transient coupling through  $C_{\text{L}A}$  and  $C_{\text{L}C}$ .

### **CMR with Other Drive Circuits**

CMR performance with drive circuits other than that shown in Figure 20 may be enhanced by following these guidelines:

- 1. Use of drive circuits where current is shunted from the LED in the LED "off" state (as shown in Figures 22 and 23). This is beneficial for good CMR<sub>H</sub>.
- 2. Use of I $_{\rm FH}$   $>$  3.5 mA. This is good for high CMR $_{\rm L}$ .

Using any one of the drive circuits in Figures 22-24 with  $I_F$  = 10 mA will result in a typical CMR of 8 kV/ $\mu$ s for the HCPL-261N family, as long as the PC board layout practices are followed. Figure 22 shows a circuit which can be used with any totem-pole-output TTL/LSTTL/HCMOS logic gate. The buffer PNP transistor allows the circuit to be used with logic devices which have low current-sinking capability. It also helps maintain the driving-gate power-supply current at a constant level to minimize ground shifting for other devices connected to the input-supply ground.

When using an open-collector TTL or open-drain CMOS logic gate, the circuit in Figure 23 may be used. When using a CMOS gate to drive the optocoupler, the circuit shown in Figure 24 may be used. The diode in parallel with the  $R_{\text{EP}}$  speeds the turn-off of the optocoupler LED.



**Figure 21. AC equivalent circuit for HCPL-261X.**



**Figure 22. TTL interface circuit for the HCPL-261A/-261N families.**



**HCPL-261A/-261N families.**



**Figure 23. TTL open-collector/open drain gate drive circuit for Figure 24. CMOS gate drive circuit for HCPL-261A/-261N families.**



## Table 1. Effects of Common Mode Pulse Direction on Transient I<sub>LE</sub>

## **Propagation Delay, Pulse-Width Distortion and Propagation Delay Skew**

Propagation delay is a figure of merit which describes how quickly a logic signal propagates through a system. The propagation delay from low to high  $(t_{\text{PlH}})$  is the amount of time required for an input signal to propagate to the output, causing the output to change from low to high. Similarly, the propagation delay from high to low  $(t_{PHI})$  is the amount of time required for the input signal to propagate to the output, causing the output to change from high to low (see Figure 9).

Pulse-width distortion (PWD) results when  $t_{PIH}$  and  $t_{PH}$ differ in value. PWD is defined as the difference between  ${\sf t}_{_{\sf PLH}}$  and  ${\sf t}_{_{\sf PLH}}$  and often determines the maximum data rate capability of a transmission system. PWD can be expressed in percent by dividing the PWD (in ns) by the minimum pulse width (in ns) being transmitted. Typically, PWD on the order of 20-30% of the minimum pulse width is tolerable; the exact figure depends on the particular application (RS232, RS422, T-1, etc.).

Propagation delay skew,  $t_{PSK}$  is an important parameter to consider in parallel data applications where synchronization of signals on parallel data lines is a concern. If the parallel data is being sent through a group of optocouplers, differences in propagation delays will cause the data to arrive at the outputs of the optocouplers at different times. If this difference in propagation delay is large enough it will determine the maximum rate at which parallel data can be sent through the optocouplers.

Propagation delay skew is defined as the difference between the minimum and maximum propagation delays, either  $t_{p<sub>PH</sub>}$  or  $t_{p<sub>HH</sub>}$ , for any given group of optocouplers which are operating under the same conditions (i.e., the same drive current, supply voltage, output load, and operating temperature). As illustrated in Figure 25, if the inputs of a group of optocouplers are switched either ON or OFF at the same time,  $t_{PSK}$  is the difference between the shortest propagation delay, either  $t_{PLH}$  or  $t_{PHL}$ , and the longest propagation delay, either  $t_{PLH}$  or  $t_{PHL}$ .

As mentioned earlier,  $t_{PSK}$  can determine the maximum parallel data transmission rate. Figure 26 is the timing diagram of a typical parallel data application with both the clock and the data lines being sent through optocouplers.